

03560.003310

PATENT APPLICATION



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor Application of:

TADASHI OKAMOTO ET AL.

Application No.: 10/601,777

Filed: June 24, 2003

For: A METHOD FOR ACQUIRING
INFORMATION OF A BIOCHIP
USING TIME OF FLIGHT
SECONDARY ION MASS
SPECTROMETRY AND AN
APPARATUS FOR ACQUIRING
INFORMATION FOR THE
APPLICATION THEREOF

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Examiner: E. Dejong

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:
Group Art Unit: 1631

)
:
January 18, 2006

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

THIRD INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Since the U.S. Patent and Trademark Office waived the requirement under 37 C.F.R. § 1.98 (a)(2)(i) for submitting a copy of each cited U.S. patent and each U.S. patent application publication for all U.S. national patent applications and for all international applications that have entered the national stage under 35 U.S.C. § 371, no copies of such documents are enclosed. Copies of the other listed documents are enclosed.

This Information Disclosure Statement is to disclose documents cited in a Search Report in a corresponding European application, which documents are not yet of record in the present case. A copy of the Search Report is enclosed.

The concise explanation of relevance for the non-English document may be found, inter alia, in the English language abstract attached thereto and/or in the European Search Report.

STATEMENT UNDER 37 C.F.R. § 1.97(e) and 1.705(d)

Each item of information in this information disclosure statement was first cited in any communication from a foreign Patent Office in a counterpart foreign application not more than three months prior to the filing date of this Statement, and this communication was not received by any individual designated in § 1.56(c) more than thirty days prior to the filing of this information disclosure statement.

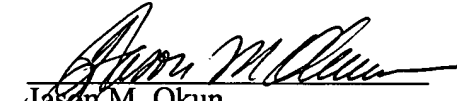
CONCLUSION

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

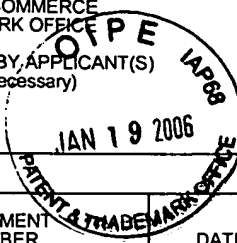
It is believed that no fee is due in connection with this Information Disclosure Statement. However, if such a fee is deemed necessary, the Commissioner is authorized to charge it to Deposit Account 06-1205. Any overpayment may be credited to the same Deposit Account.

Applicants' undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

Respectfully submitted,

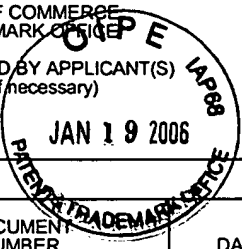

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03560.003310		APPLICATION NO. 10/601,777	
				APPLICANT Tadashi Okamoto et al.			
				FILING DATE June 24, 2003		GROUP 1631	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,589,685	12/31/96	Jen Wu et al.	250	282	
		6,002,128	12/14/99	Hill et al.	250	287	
		2001/0055813 A1	12/27/01	Winograd et al.	436	89	
		5,821,060	10/13/98	Arlinghaus et al.	435	6	
		2002/0074517 A1	06/20/02	Krutchinsky et al.	250	492.1	
		4,983,831	01/08/91	Migeon et al.	250	309	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	DE	31 44 604 A1	05/19/83	Germany			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		Steven M. Hues et al., "A Pulsed Alkali-Ion Gun for Time-of-Flight Secondary Ion Mass Spectrometry," 60(7) <u>Rev. Sci. Instrum.</u> 1239-44 (July 1989).					
		Viswanatham Katta et al., "A Pulsed Ion Bombardment Time-of-Flight Mass Spectrometer with High Sensitivity for the Analysis of Peptides," 105 <u>Int. J. Mass Spectrom. Ion Processes</u> 129-45 (1991).					
		J. Schwieters et al., "High Mass Resolution Surface Imaging with Time-of-Flight Secondary Ion Mass Spectroscopy Scanning Microprobe," 9(6) <u>J. Vac. Sci. Technol.</u> 2864-71 (1991).					
		Robert W. Odom, "Secondary Ion Mass Spectrometry Imaging," 29(1) <u>Appl. Spectros. Rev.</u> 67-116 (February 1994).					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	G.C. Rider et al., "Imaging Time-of-Flight SIMS - A New Technique for Spatially-Resolved Chemical Surface Analysis," 4(1) J. Molecul. Electron. 402 (1988) (Abstract).
	Anthony J. Nicola et al., "Enhancement of Ion Intensity in Time-of-Flight Secondary-Ionization Mass Spectrometry," 7 J. Am. Soc. Mass Spectrom. 467-71 (1996).

EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 2 of 2